

Form PTO-1449 (Modified)		Atty Docket No.: P18612		Serial No.: Unknown	
List of Patents and Publications Statement (Use several sheets if necessary)				Applicant: Uday Shah et al.	
				Filing Date: March 24, 2004	

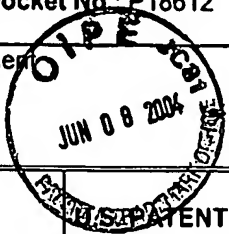
  

REFERENCE DESIGNATION			U.S. PATENT DOCUMENTS			
Examiner Initials	Document No.	Class	Sub-Class	Filing date if appropriate		
AC	AA	6,063,698	Tseng et al.	438	585	
	AB	6,184,072 B1	Kaushik et al.	438	197	
	AC	6,420,279 B1	Ono et al.	438	785	
	AD	6,475,874 B2	Xiang et al.	438	396	
	AE	6,514,828 B2	Ahn et al.	438	240	
	AF	6,544,906 B2	Rotondaro et al.	438	785	
	AG	6,617,209 B1	Chau et al.	438	240	
	AH	6,617,210 B1	Chau et al.	438	240	
	AI	6,620,713 B2	Arghavani et al.	438	585	
	AJ	6,689,675 B1	Parker et al.	438	585	
	AK	6,696,327 B1	Brask et al.	438	197	
	AL	6,696,345 B2	Chau et al.	438	387	
	AM	US2002/0197790 A1	Kizilyalli et al.	438	240	
	AN	US2003/0032303 A1	Yu et al.	438	770	
	AO	US2003/0045080 A1	Visokay et al.	438	591	
	FOREIGN PATENT DOCUMENTS					
		Document No.	Date	Country	Class	Sub-Class
AP						
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)						
AC	AQ	Polishchuk et al., "Dual Workfunction CMOS Gate Technology Based on Metal Interdiffusion", <a href="http://www.eesc.berkeley.edu">www.eesc.berkeley.edu</a> , 1 page				
	AR	Doug Barlage et al., "High-Frequency Response of 100nm Integrated CMOS Transistors with High-K Gate Dielectrics", 2001 IEEE, 4 pages				
	AS	Lu et al., "Dual-Metal Gate Technology for Deep-Submicron CMOS Devices", dated April 29, 2003, 1 page				
	AT	Schwantes et al., "Performance Improvement of Metal Gate CMOS Technologies with Gigabit Feature Sizes", Technical University of Hamburg-Harburg, 5 pages				
	AU	Doczy et al., "Integrating N-type and P-type Metal Gate Transistors," Serial No. 10/327,293, Filed December 20, 2002				
	AV	Brask et al., "A Method for Making a Semiconductor Device Having a Metal Gate Electrode," Serial No. 10/704,497, Filed November 6, 2003				
	AW	Brask et al., "A Method for Etching a Thin Metal Layer", Serial No. 10/704,498, Filed November 6, 2003				
	AX	Brask et al., "A Method for Making a Semiconductor Device with a Metal Gate Electrode that is Formed on an Annealed High-K Gate Dielectric Layer", Serial No. 10/742,678, Filed 12/19/03				
	AY	Brask et al., "A Method for Making a Semiconductor Device that Includes a Metal Gate Electrode", Serial No. 10/739,173, filed December 18, 2003				
	AZ	Brask et al., "A CMOS Device With Metal and Silicide Gate Electrodes and a Method for Making It", Serial No. 10/748,559, filed December 29, 2003				
AC	BA	Doczy et al., "A Method for Making a Semiconductor Device that Includes a Metal Gate Electrode", Serial No. 10/748,545, filed December 29, 2003				
	<div style="display: flex; justify-content: space-between;"> <div>Examiner <i>Anthony Chambliss</i></div> <div>Date Considered <i>5/1/06</i></div> </div>					

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Form PTO-1449 (Modified)	Atty Docket No.: P18612	Serial No.: 10/809,853
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		Filing Date: April 20, 2004



REFERENCE DESIGNATION						
Examiner Initials	Document No.	Class	Sub-Class	Filing date if appropriate		
AC	AA	6,365,450 B1	Kim	438	216	
	AB					
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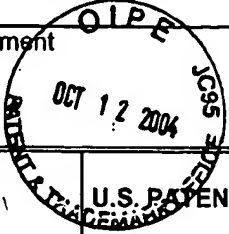
FOREIGN PATENT DOCUMENTS							
Document No.	Date	Country	Class	Sub-Class	Translation		
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
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Examiner: <i>Alonso Chamilis</i>	Date Considered: <i>5/1/06</i>
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REFERENCE DESIGNATION			U.S. PATENT DOCUMENTS			
Examiner Initials	Document No.	Document No.	Class	Sub-Class	Filing date if appropriate	
AC	AA	6,255,698 B1	Gardner et al.	257	369	
	AB	6,410,376 B1	Ng et al.	438	199	
AC	AC	6,586,288 B2	Kim et al.	438	183	
	AD	US 2002/0058374 A1	Kim et al.	438	228	
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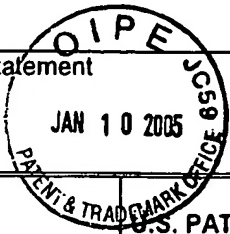
FOREIGN PATENT DOCUMENTS							
Document No.	Date	Country	Class	Sub-Class	Translation		
AC AP	EP 0 899 784 AZ	3/3/1999					
AC AQ	GB 2 358 737 A	4/24/2001					
AR							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
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Examiner: <i>Adamo Chambers</i>	Date Considered: 5/1/04
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REFERENCE DESIGNATION						
Examiner Initials	Document No.	Class	Sub-Class	Filing date if appropriate		
<del>           AC            AC         </del>	AA	6,642,131 B2	Harada	438	591	
	AB	6,667,246 B2	Mitsuhashi et al.	438	756	
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Examiner: <i>Alamp Chandra</i>	Date Considered: <i>5/1/06</i>
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